Abstracts

Experimental verification of pattern selection for noise characterization

S. Van den Bosch and L. Martens. "Experimental verification of pattern selection for noise characterization." 2000 Transactions on Microwave Theory and Techniques 48.1 (Jan. 2000 [T-MTT]): 156-158.

A comparison is made between different pattern-selection procedures for noise characterization based on measurements of cold-FETs in a common-source configuration. The measurements were performed using an automated noise setup with one electro-mechanical tuner. The results confirm that a recently developed two-step pattern allows more accurate noise-parameter determination compared to existing practice. The significance of this paper lies in the confirmation of the simulation results presented earlier.

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